Se	arc	hΛ	lote	es	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/089,805	YANG ET AL.	
Examiner	Art Unit	
Naheed Ejaz	2611	

SEARCHED				
Class	Subclass	Date	Examiner	
375	130,140, 147,259, 271,272 279	9/21/2006	NE	
375	316,320	9/21/2006	NE	
375	322,324	9/21/2006	NE	
375	326,329	9/21/2006	NE	
375	354,362	9/21/2006	NE	
329	304,315	9/21/2006	NE	
329	341,343	9/21/2006	NE	

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
375	329	9/21/2006	NE	
375	322,324	9/21/2006	NE	
329	315	9/21/2006	NE	
375/130,140,147,259, 271,272,279,316,320, 326,354,362		9/21/2006	NE	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST search attached	9/21/2006	NE
Consulted with Primary Examiner Pankaj Kumar	9/19/2006	NE